

COXEM CO., LTD

COXEM is a market-leading manufacturer of Scanning Electron Microscopes. We offer both bench-top SEM and console or full-size SEM with various optional features such as STEM and Cold Stage. COXEM has recently expanded its product line by providing a large area particle analyzer, SELPA.

COXEM is dedicated to serving all customers in a wide range of scientific fields with its high-quality products and optimized solutions.

- **EM-30^N (Scanning Electron Microscope)**

The EM-30^N is our most advanced tungsten filament base Table-Top SEM. Featuring our new DSP (Digital Signal Processing) technology, the EM-30^N provides clear, low noise images at high magnification. Now available with LV (Low Vacuum), you can produce clean, quality images of non-conductive samples without coating. The EM-30^N is also the world's first table top SEM available with compact EBSD.

- **EM-30^C (Scanning Electron Microscope)**

The EM-30^C is an advanced tabletop SEM which uses a CeB6 (Cerium Hexaboride) electron gun source, providing 10x higher brightness and longer cathode life compared to a tungsten filament. This allows the EM-30^C to provide quality results and analysis in a variety of applications in research and industrial quality control. Now you can experience 10 times brighter and clearer images with EM-30^C.

- **SELPA (Scanning Electron Particle Analyzer)**

SELPA is an automated large area particle analyzer based on SEM and EDS. Not only can the SELPA detect micro-particles on large areas (max. 100 x 100mm), but it can also classify particles by their various size and elements by referencing the included data base. By automating these features in a compact, easy-to-use package, SELPA can provide analysis solutions in many industrial fields such as cleanliness, steel inclusion, GSR, mineral analysis, asbestos, etc.

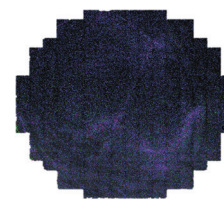
- **CP-8000+ (Ion Beam Cross-section Polisher)**

The CP-8000+ is an ion milling system which uses an Argon ion beam to polish a variety of difficult to prepare samples without crushing, cracking, fatigue failure, or any chemical damage. The CP-8000+ is also an ideal tool for sample preparation to analyze cross-sections. With its ability to prepare larger cross-sections than a FIB with less damage than a mechanical polisher, the CP-8000+ provides fast and efficient sample preparation at an affordable price.

COXEM's SEM & Ion Milling System solution can be used in many fields of research and industries such as automotive, batteries, pharmaceutical, multi-layer materials, capacitors, semi-conductors and more.

As one of the fastest growing electron microscope brands, COXEM microscopes can be found all over the world in hundreds of global universities, labs, government research centers and industrial companies.

COXEM is based in South Korea with distributors located world-wide.



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